



WEBINARS

Join us for a **FREE Webinar**

High-Resolution Measurement of Film Thickness and Refractive Index for Silicon Photonics and Planar Waveguide Applications

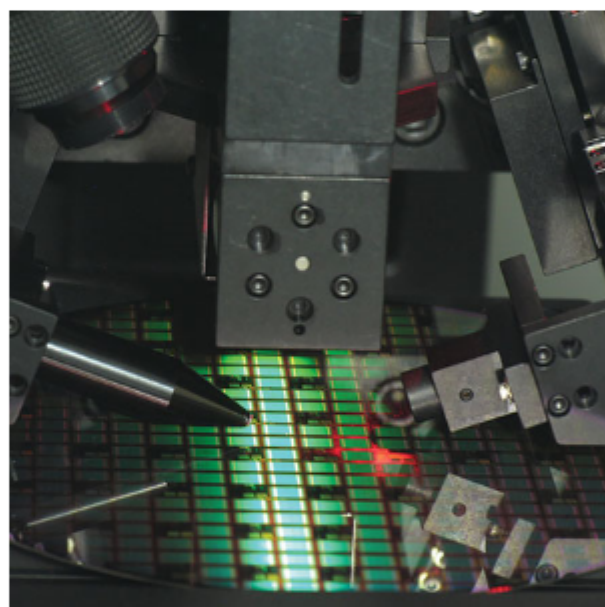
Wednesday, December 6, 2023 1:00 PM - 2:00 PM EST

[Register Now](#)

Presented by



This webinar provides an overview of advanced measurement technologies tailored to meet the high-resolution demands of silicon photonics and planar waveguide applications. Lawrence Rooney of Bruker shares about state-of-the-art film thickness and refractive index measurement techniques, including multi-angle spectroscopic reflectometry and ellipsometry, and discusses their respective advantages, limitations, and suitability for different types of multi-layer photonic structures. He also highlights the critical importance of high-resolution film thickness and refractive index measurement techniques in the advancement of silicon photonics and planar waveguide applications. Presented by [Bruker](#).



Upcoming Webinars

- [The Etendue Mystery Revealed](#), 11/28/2023 10:00:00 AM EST
- [Design and Optimization of Optical Waveguides](#), 11/30/2023 2:00:00 PM EST
- [Quantum Efficiency Measurements: Fundamentals for Solar Cell Research, Part 1](#), 12/5/2023 1:00:00 PM EST

Archived Webinars

- [Optimization of Surface Enhanced Spatially Offset Raman Spectroscopy for Applications in Pre-Clinical Cancer Imaging](#)
- [Next-Generation Instrumentation for Optical Control and Characterization](#)
- [Mastering Diffraction Gratings: Selection and Integration Techniques for Analytical Instrumentation](#)

Don't miss out!

Sign up for our [Webinar Alerts](#) email today and never miss an upcoming event.

We respect your time and privacy. You are receiving this email because you are a Photonics Spectra magazine subscriber. You may use the links below to manage your subscriptions or contact us.

Questions: info@photonics.com

[Unsubscribe](#) | [Subscribe](#) | [Subscriptions](#) | [Privacy Policy](#) | [Terms and Conditions of Use](#)

Photonics Media, 100 West St., PO Box 4949, Pittsfield, MA 01202-4949

© 1996 - 2023 Laurin Publishing. All rights reserved. Photonics.com is Registered with the U.S. Patent & Trademark Office. Reproduction in whole or in part without permission is prohibited.